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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Not for submission under 37 CFR 1.99)	Application Number		10536483	
	Filing Date		2005-05-24	
	First Named Inventor	Bruce B. Doris		
	Art Unit	2826		
	Examiner Name	Benjamin T. Liu		
	Attorney Docket Number	6798		

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Examiner Initial*	Cite No	Patent Number	Kind Code ¹	Issue Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines where Relevant Passages or Relevant Figures Appear		
BTL	1	6342410		2002-01-29	Yu			
BTL	2	6573172		2003-06-03	En et al.			
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BTL	1	20030040158		2003-02-27	Saitoh			
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Attorney Docket Number		6798	

Examiner Initials*	Cite No	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, pages(s), volume-issue number(s), publisher, city and/or country where published.	T ⁵
BTL	1	A. Shimizu et al., "Local Mechanical-Stress Control (LMC): A New Technique for CMOS-Performance Enhancement", International Electron Devices Meeting 2001. IEDM Technical Digest. 2001 IEEE, pp. 19.4.1-19.4.4.	<input type="checkbox"/>
BTL	2	S. Ito et al., "Effect of Mechanical Stress Induced by Etch-Stop Nitride: Impact on Deep-Submicron Transistor Performance", Microelectronics and Reliability, Elsevier Science Ltd., GB, vol. 42, no. 2, February 2002, pages 201-209.	<input type="checkbox"/>
BTL	3	S. Ito et al., "Mechanical Stress Effect of Etch-Stop Nitride and its Impact on Deep Submicron Transistor Design", IEDM Technical Digest, 2000 IEEE, pp. 10.7.1-10.7.4.	<input type="checkbox"/>

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Examiner Signature	/Benjamin Tzu-Hung Liu	Date Considered/	(09/13/2006)
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¹ See Kind Codes of USPTO Patent Documents at www.USPTO.GOV or MPEP 901.04. ² Enter office that issued the document, by the two-letter code (WIPO Standard ST.3). ³ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁴ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁵ Applicant is to place a check mark here if English language translation is attached.

INFORMATION DISCLOSURE STATEMENT
(Use several sheets if necessary)

Docket Number (Optional)

FIS920020105

Application Number

10/536483

Applicant(s)

Doris, et al.

Filing Date

11/25/02

Group Art Unit

2826

To be assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		3,602,841	8-31-71	McGroddy			
		4,665,415	5-12-87	Esaki, et al.			
		4,853,076	8-1-89	Tsaur, et al.			
		4,855,245	8-8-89	Neppl, et al.			
		4,952,524	8-28-90	Lee, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		US 2001/0009784 A1	7-26-01	Ma, et al.			
		US 2002/0063292 A1	5-30-02	Armstrong, et al.			
		US 2002/0074598 A1	6-20-02	Doyle, et al.			
		US 2002/0086472	7-4-02	Roberds, et al.			

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
BTL		JP64-76755	03-1989	Japan				

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

BTL		Kern Rim, et al., "Transconductance Enhancement in Deep Submicron Strained-Si n-MOSFETs". International Electron Devices Meeting, 26, 8, 1, IEEE, September 1998.
BTL		Kern Rim, et al., "Characteristics and Device Design of Sub-100 nm Strained Si N- and PMOSFETs." 2002 Symposium on VLSI Technology Digest of Technical Papers, IEEE, pp. 98-99.

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107556483

Applicant(s)

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Filing Date

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U.S. PATENT DOCUMENTS

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BTL		4,958,213	9-18-90	Eklund, et al.			
BTL		5,006,913	4-9-91	Sugahara, et al.			
BTL		5,060,030	10-22-91	Hoke, et al.			
BTL		5,081,513	1-14-92	Jackson, et al.			
BTL		5,108,843	4-28-92	Ohtaka, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		US 2002/0086497 A1	7-4-02	Kwok			
BTL		US 2002/0090791 A1	7-11-02	Doyle, et al.			
BTL		US 2003/0032261 A1	2-13-03	Yeh, et al.			
BTL		US 2003/0040158 A1	2-27-03	Saltob			

FOREIGN PATENT DOCUMENTS

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							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

BTL		Gregory Scott, et al., "NMOS Drive Current Reduction Caused by Transistor Layout and Trench Isolation Induced Stress." International Electron Devices Meeting, 34.4.1, IEEE, September 1999.
BTL		F. Ootsuka, et al., "A Highly Dense, High-Performance 130nm Node CMOS Technology for Large Scale System-on-a-Chip Application." International Electron Devices Meeting, 23.5.1, IEEE, April 2000.

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,134,085	7-28-92	Gilgen, et al.			
BTL		5,310,446	5-10-94	Konishi, et al.			
BTL		5,354,695	10-11-94	Leedy			
BTL		5,371,399	12-6-94	Burroughes, et al.			
BTL		5,391,510	2-21-95	Hsu, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		US 2003/0057184 A1	3-27-03	Yu, et al.			
BTL		US 2003/0067035 A1	4-10-03	Tews, et al.			

FOREIGN PATENT DOCUMENTS

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BTL		Shinya Ito, et al., "Mechanical Stress Effect of Etch-Stop Nitride and its Impact on Deep Submicron Transistor Design." International Electron Devices Meeting, 10.7.1, IEEE, April 2000.
BTL		A. Shimizu, et al., "Local Mechanical-Stress Control (LMC): A New Technique for CMOS-Performance Enhancement." International Electron Devices Meeting, IEEE, March 2001.

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Applicant(s)

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Filing Date

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Group Article

2826

To be assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,459,346	10-17-95	Asakawa, et al.			
BTL		5,471,948	12-5-95	Burroughes, et al.			
BTL		5,557,122	9-17-96	Shrivastava, et al.			
BTL		5,561,302	10-1-96	Candelaria			
BTL		5,565,697	10-15-96	Asakawa, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

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OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

BTL		K. Ota, et al., "Novel Locally Strained Channel Technique for High Performance 55nm CMOS." International Electron Devices Meeting, 2.2.1, IEEE, February 2002.
BTL		G. Zhang, et al., "A New 'Mixed-Mode' Reliability Degradation Mechanism in Advanced Si and SiGe Bipolar Transistors." IEEE Transactions on Electron Devices, vol. 49, no. 12, December 2002, pp. 2151-56.

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Applicant(s)

Doris, et al.

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Group Art Unit

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,571,741	11-5-96	Leedy			
BTL		5,592,007	1-7-97	Leedy			
BTL		5,592,018	1-7-97	Leedy			
BTL		5,670,798	9-23-97	Schetzina			
BTL		5,679,965	10-21-97	Schetzina			

U.S. PATENT APPLICATION PUBLICATIONS

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							YES	NO

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

BTL		H.S. Momose, et al., "Temperature Dependence of Emitter-Base Reverse Stress Degradation and Its Mechanism Analyzed by MOS Structures." Paper 6.2, pp. 140-143.
BTL		C.J. Huang, et al., "Temperature Dependence and Post-Stress Recovery of Hot Electron Degradation Effects in Bipolar Transistors." IEEE 1991 Bipolar Circuits and Technology Meeting 7.5, pp. 170-173.

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INFORMATION DISCLOSURE CITATION
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FIS920020105

Applicant(s)

Doris, et al.

Filing Date

11/25/02

Application Number

To be assigned 10/536483

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2826

To be assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REP	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,683,934	11-4-97	Candelaria			
BTL		5,840,593	11-24-98	Leedy			
BTL		5,861,651	1-19-99	Brasen, et al.			
BTL		5,880,040	3-9-99	Sun, et al.			
BTL		5,940,716	8-17-99	Jin, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REP	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	REP	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

BTL		S.R. Sheng, et al., "Degradation and Recovery of SiGe HBTs Following Radiation and Hot-Carrier Stressing." Pp. 14-15.
BTL		Z. Yang, et al., "Avalanche Current Induced Hot Carrier Degradation in 200 GHz SiGe Heterojunction Bipolar Transistors." Pp. 1-5.

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FIS920020105

Applicant(s)

Doris, et al.

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11/25/02

Applicant's Number
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Group Art Unit

2826

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,940,736	8-17-99	Brady, et al.			
BTL		5,946,559	8-31-99	Leedy			
BTL		5,960,297	9-28-99	Saki			
BTL		5,989,978	11-23-99	Peidous			
BTL		6,008,126	12-28-99	Leedy			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translations	
							YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

BTL		H. Li, et al., "Design of W-Band VCOs with High Output Power for Potential Application in 77 GHz Automotive Radar Systems." 2003 IEEE GaAs Digest, pp. 263-66.
BTL		H. Wurzer, et al., "Annealing of Degraded npn-Transistors- Mechanisms and Modeling." IEEE Transactions on Electron Devices, vol. 41, no. 4, April 1994, pp. 533-38.

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		6,025,280	2-15-00	Brady, et al.			
BTL		6,046,464	4-4-00	Schetzina			
BTL		6,066,545	5-23-00	Doshi, et al.			
BTL		6,090,684	7-18-00	Ishitsuka, et al.			
BTL		6,107,143	8-22-00	Park, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

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FOREIGN PATENT DOCUMENTS

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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

BTL		B. Doyle, et al., "Recovery of Hot-Carrier Damage in Reoxidized Nitrided Oxide MOSFETs." IEEE Electron Device Letters, vol. 13, no. 1, January 1992, pp. 38-40.
BTL		H.S. Momose, et al., "Analysis of the Temperature Dependence of Hot-Carrier-Induced Degradation in Bipolar Transistors for Bi-CMOS." IEEE Transactions on Electron Devices, vol. 41, no. 6, June 1994, pp. 978-987.

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U.S. PATENT DOCUMENTS

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BTL		6,117,722	9-12-00	Wuu, et al.			
BTL		6,133,071	10-17-00	Nagai			
BTL		6,165,383	12-26-00	Chou			
BTL		6,221,735	4-24-01	Manley, et al.			
BTL		6,228,694	5-8-01	Doyle, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

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107536483

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BTL		6,246,095	6-12-01	Brady, et al.			
BTL		6,255,169	7-3-01	Li, et al.			
BTL		6,261,964	7-17-01	Wu, et al.			
BTL		6,265,317	7-24-01	Chiu, et al.			
BTL		6,274,444	8-14-01	Wang			

U.S. PATENT APPLICATION PUBLICATIONS

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BTL		6,281,532	8-28-01	Doyle, et al.			
BTL		6,284,623	9-4-01	Zhang, et al.			
BTL		6,284,626	9-4-01	Kim			
BTL		6,319,794	11-20-01	Akatsu, et al.			
BTL		6,361,885	3-26-02	Chou			

U.S. PATENT APPLICATION PUBLICATIONS

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BTL		6,362,082	3-26-02	Doyle, et al.			
BTL		6,368,931	4-9-02	Kuhn, et al.			
BTL		6,403,486	6-11-02	Lou			
BTL		6,403,975	6-11-02	Brunner, et al.			
BTL		6,406,973	6-18-02	Lee			

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BTL		6,461,936	10-8-02	von Ehrenwall			
BTL		6,476,462	11-5-02	Shimizu, et al.			
BTL		6,483,171	11-19-02	Forbes, et al.			
BTL		6,493,497	12-10-02	Ramdani, et al.			
BTL		6,498,358	12-24-02	Lach, et al.			

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1000 Rec'd PCT/PTO 24 MAY 2003

INFORMATION DISCLOSURE CITATION
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Docket Number (Optional)

FIS920020105

Application Number

To be assigned

10/536483

Applicant(s)

Doris, et al.

Filing Date

11/25/02

Group Art Unit

To be assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		6,501,121	12-31-02	Yu, et al.			
BTL		6,506,652	1-14-03	Jan, et al.			
BTL		6,509,618	1-21-03	Jan, et al.			
BTL		6,521,964	2-18-03	Jan, et al.			
BTL		6,531,369	3-11-03	Ozkan, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

OTHER DOCUMENTS

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2826

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		6,531,740	3-11-03	Bosco, et al.			
BTL		6,621,392	9-16-03	Volant, et al.			
BTL		6,635,506	10-21-03	Volant, et al.			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

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*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		6,342,410	1-29-02	Yu			
BTL		6,413,802	7-2-02	Hu, et al.			
BTL		6,433,609	8-13-02	Voldman			
BTL		6,458,662	10-1-02	Yu			

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
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